Chip Monolithic Ceramic Capacitors

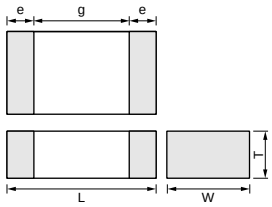
Low-dissipation Type

■ Features

1. Mobile telecommunication and RF module, mainly
2. Quality improvement of telephone calls, Low power consumption, yield ratio improvement

■ Applications

VCO, PA, Mobile Telecommunications



Part Number	Dimensions (mm)				
	L	W	T	e	g min.
GJM15	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4
GJM03	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GJM1555C1HR50CB01	C0G (EIA)	50	0.50 ±0.25pF	1.00	0.50	0.50
GJM1555C1HR75CB01	C0G (EIA)	50	0.75 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R0CB01	C0G (EIA)	50	1.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R1CB01	C0G (EIA)	50	1.1 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R2CB01	C0G (EIA)	50	1.2 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R3CB01	C0G (EIA)	50	1.3 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R5CB01	C0G (EIA)	50	1.5 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R6CB01	C0G (EIA)	50	1.6 ±0.25pF	1.00	0.50	0.50
GJM1555C1H1R8CB01	C0G (EIA)	50	1.8 ±0.25pF	1.00	0.50	0.50
GJM1555C1H2R0CB01	C0G (EIA)	50	2.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H2R2CB01	C0G (EIA)	50	2.2 ±0.25pF	1.00	0.50	0.50
GJM1555C1H2R4CB01	C0G (EIA)	50	2.4 ±0.25pF	1.00	0.50	0.50
GJM1555C1H2R7CB01	C0G (EIA)	50	2.7 ±0.25pF	1.00	0.50	0.50
GJM1555C1H3R0CB01	C0G (EIA)	50	3.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H3R3CB01	C0G (EIA)	50	3.3 ±0.25pF	1.00	0.50	0.50
GJM1555C1H3R6CB01	C0G (EIA)	50	3.6 ±0.25pF	1.00	0.50	0.50
GJM1555C1H3R9CB01	C0G (EIA)	50	3.9 ±0.25pF	1.00	0.50	0.50
GJM1555C1H4R0CB01	C0G (EIA)	50	4.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H4R3CB01	C0G (EIA)	50	4.3 ±0.25pF	1.00	0.50	0.50
GJM1555C1H4R7CB01	C0G (EIA)	50	4.7 ±0.25pF	1.00	0.50	0.50
GJM1555C1H5R0CB01	C0G (EIA)	50	5.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H5R1CB01	C0G (EIA)	50	5.1 ±0.25pF	1.00	0.50	0.50
GJM1555C1H5R6CB01	C0G (EIA)	50	5.6 ±0.25pF	1.00	0.50	0.50
GJM1555C1H6R0CB01	C0G (EIA)	50	6.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H6R0DB01	C0G (EIA)	50	6.0 ±0.5pF	1.00	0.50	0.50
GJM1555C1H6R2CB01	C0G (EIA)	50	6.2 ±0.25pF	1.00	0.50	0.50
GJM1555C1H6R8CB01	C0G (EIA)	50	6.8 ±0.25pF	1.00	0.50	0.50
GJM1555C1H7R0CB01	C0G (EIA)	50	7.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H7R0DB01	C0G (EIA)	50	7.0 ±0.5pF	1.00	0.50	0.50
GJM1555C1H7R5CB01	C0G (EIA)	50	7.5 ±0.25pF	1.00	0.50	0.50
GJM1555C1H8R0CB01	C0G (EIA)	50	8.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H8R0DB01	C0G (EIA)	50	8.0 ±0.5pF	1.00	0.50	0.50
GJM1555C1H8R2CB01	C0G (EIA)	50	8.2 ±0.25pF	1.00	0.50	0.50
GJM1555C1H9R0CB01	C0G (EIA)	50	9.0 ±0.25pF	1.00	0.50	0.50
GJM1555C1H9R0DB01	C0G (EIA)	50	9.0 ±0.5pF	1.00	0.50	0.50
GJM1555C1H9R1CB01	C0G (EIA)	50	9.1 ±0.25pF	1.00	0.50	0.50
GJM1555C1H100JB01	C0G (EIA)	50	10 ±5%	1.00	0.50	0.50
GJM1555C1H100RB01	C0G (EIA)	50	10 ±2.5%	1.00	0.50	0.50

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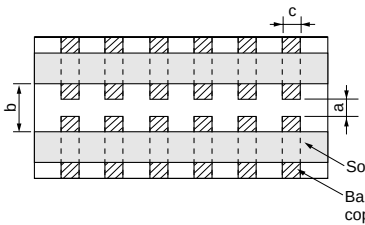
Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GJM1555C1H120JB01	C0G (EIA)	50	12 ±5%	1.00	0.50	0.50
GJM1555C1H150JB01	C0G (EIA)	50	15 ±5%	1.00	0.50	0.50
GJM1555C1H180JB01	C0G (EIA)	50	18 ±5%	1.00	0.50	0.50

Specifications and Test Methods

No.	Item		Specifications: Temperature Compensating Type	Test Method
1	Operating Temperature Range		−55 to +125℃	
2	Rated Voltage		See the previous pages	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V^{P-P} or V^{O-P}, whichever is larger, should be maintained within the rated voltage range.
3	Appearance		No defects or abnormalities	Visual inspection
4	Dimensions		Within the specified dimensions	Using calipers
5	Dielectric Strength		No defects or abnormalities	No failure should be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.
6	Insulation Resistance (I.R.)		10,000MΩ min. or 500Ω • F min. (Whichever is smaller)	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25℃ and 75%RH max. and within 2 minutes of charging.
7	Capacitance		Within the specified tolerance	The capacitance/Q should be measured at 25℃ at the frequency and voltage shown in the table.
8	Q		30pF max. : Q≧400+20C C : Nominal Capacitance (pF)	
9	Capacitance Temperature Characteristics	Capacitance Change	Within the specified tolerance (Table A)	The capacitance change should be measured after 5 min. at each specified temperature stage. Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5, (ΔC : +25℃ to+125℃ : other temp. coeffs. : +25℃ to 85℃) the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in steps 1, 3 and 5 by the capacitance value in step 3.
		Temperature Coefficient	Within the specified tolerance (Table A)	
		Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.)	
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply a 5N* force in parallel with the test jig for 10±1sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *2N (GJM03)

Item \ Char.	ΔC (1000pF and below)
Frequency	1±0.1MHz
Voltage	0.5 to 5Vr.m.s.

Step	Temperature (℃)
1	25±2
2	−55±3
3	25±2
4	125±3
5	25±2



Type	a	b	c
GJM03	0.3	0.9	0.3
GJM15	0.4	1.5	0.5

(in mm)

Fig. 1

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Specifications and Test Methods

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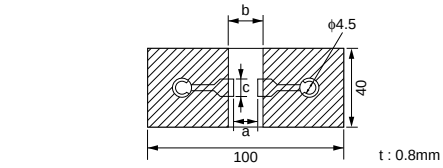
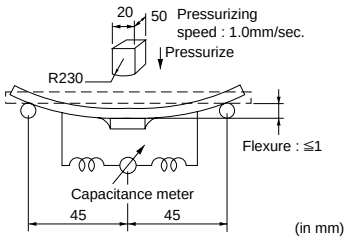
No.	Item		Specifications Temperature Compensating Type	Test Method
11	Vibration Resistance	Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).
		Capacitance	Within the specified tolerance	
		Q	30pF max. : Q≧400+20C C : Nominal Capacitance (pF)	
12	Deflection		No cracking or marking defects should occur  (in mm) Fig. 2	Solder the capacitor to the test jig (glass epoxy boards) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.  Fig. 3
13	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5℃.
14	Resistance to Soldering Heat		The measured and observed characteristics should satisfy the specifications in the following table.	Preheat the capacitor at 120 to 150℃ for 1 minute. Immerse the capacitor in a eutectic solder solution at 270±5℃ for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.
		Appearance	No marking defects	
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	
		Q	30pF and below : Q≧400+20C C : Nominal Capacitance (pF)	
		I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
15	Temperature Cycle		The measured and observed characteristics should satisfy the specifications in the following table.	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature, then measure. Step 1: Min. Operating Temp. $^{+0}_{-3}$ (30±3) — Step 2: Room Temp. (2 to 3) — Step 3: Max. Operating Temp. $^{+3}_{-0}$ (30±3) — Step 4: Room Temp. (2 to 3)
		Appearance	No marking defects	
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	
		Q	30pF and below : Q≧400+20C C : Nominal Capacitance (pF)	
		I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
16	Humidity, Steady State		The measured and observed characteristics should satisfy the specifications in the following table.	Let the capacitor sit at 40±2℃ and 90 to 95% humidity for 500±12 hours. Remove and let sit for 24±2 hours (temperature compensating type) at room temperature, then measure.
		Appearance	No marking defects	
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	
		Q	10pF and over, 30pF and below : Q≧275+$\frac{5}{2}$C 10pF and below : Q≧200+10C C : Nominal Capacitance (pF)	
		I.R.	More than 10,000MΩ or 500Ω • F (Whichever is smaller)	

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Specifications and Test Methods

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No.	Item		Specifications Temperature Compensating Type	Test Method
17	Humidity Load		The measured and observed characteristics should satisfy the specifications in the following table.	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for 500±12 hours. Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
		Appearance	No marking defects	
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	
		Q	30pF and below : Q≧100+$\frac{10}{3}$C C : Nominal Capacitance (pF)	
		I.R.	More than 500MΩ or 25Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
18	High Temperature Load		The measured and observed characteristics should satisfy the specifications in the following table.	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3℃. Let sit for 24±2 hours (temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.
		Appearance	No marking defects	
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	
		Q	10pF and over, 30pF and below : Q≧275+$\frac{5}{2}$C 10pF and below : Q≧200+10C C : Nominal Capacitance (pF)	
		I.R.	More than 1,000MΩ or 50Ω • F (Whichever is smaller)	
		Dielectric Strength	No failure	
19	ESR		0.5pF≦C≦1pF : 350mΩ • pF below 1pF<C≦5pF : 300mΩ below 5pF<C≦10pF : 250mΩ below	The ESR should be measured at room Temperature. and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.
			10pF<C≦20pF : 400mΩ below	The ESR should be measured at room Temperature. and frequency 500±50MHz with the equivalent of HP8753B.

Table A

Char. Code	Temp. Coeff. (ppm/℃) Note 1	Capacitance Change from 25℃ Value (%)					
		−55℃		−30℃		−10℃	
		Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	−0.24	0.40	−0.17	0.25	−0.11

Note 1 : Nominal values denote the temperature coefficient within a range of 25 to 125℃.(for ΔC)